

Computer Simulations (MD & EMS) For the Determination of the Imaging Conditions in the Study of *Solid-Liquid Interfaces* by HRTEM

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Introduction:

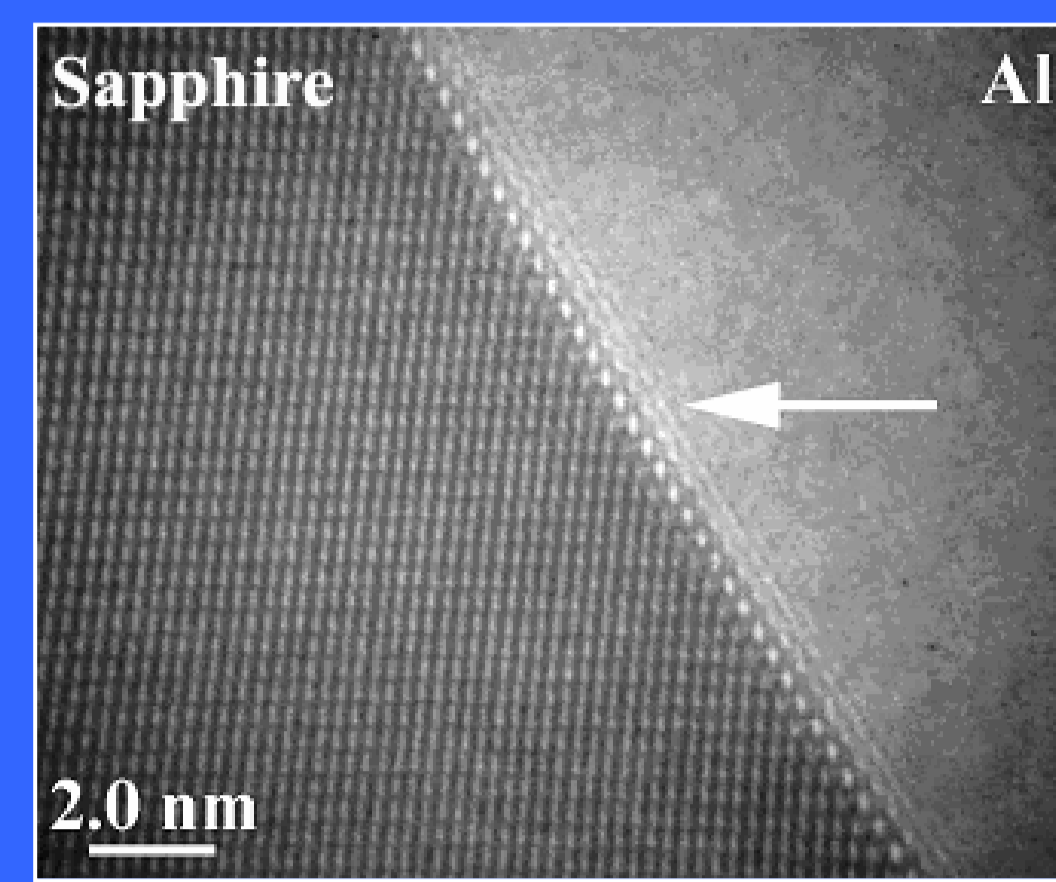
Understanding the nature of *solid-liquid interfaces* is very important for many **processes of technological interest**, such as:

- Solidification
- Epitaxial growth
- Wetting
- Liquid phase joining
- Crystal growth
- Lubrication

Characterization of the atomistic structure of an interface, and in particular interfaces between solids and liquids, is a **very challenging experimental problem**.

Molecular dynamics simulations [1] showed the presence of a **layering effect** in the liquid induced by the presence of a crystal. In some cases even **in-plane ordering** was observed.

The limited number of studies done by **HRTEM** [2,3] also point to the existence of a layering effect at the solid-liquid interface.



HRTEM micrograph of liquid Al in contact with sapphire. The contrast perturbations in the liquid, immediately adjacent and parallel to the (0001) sapphire surface, indicate ordering within the liquid Al. The contrast perturbations are not an artifact, and exist over a range of objective lens defocus. Data acquired by C. Scheu on the MPI ARM, at 750°C.

The main problem with direct HRTEM investigations: **The imaging conditions have a significant influence on the contrast in the image, and may lead to inaccurate conclusions !!!**

The main controllable parameters that may affect the resulting lattice image acquired by HRTEM are:

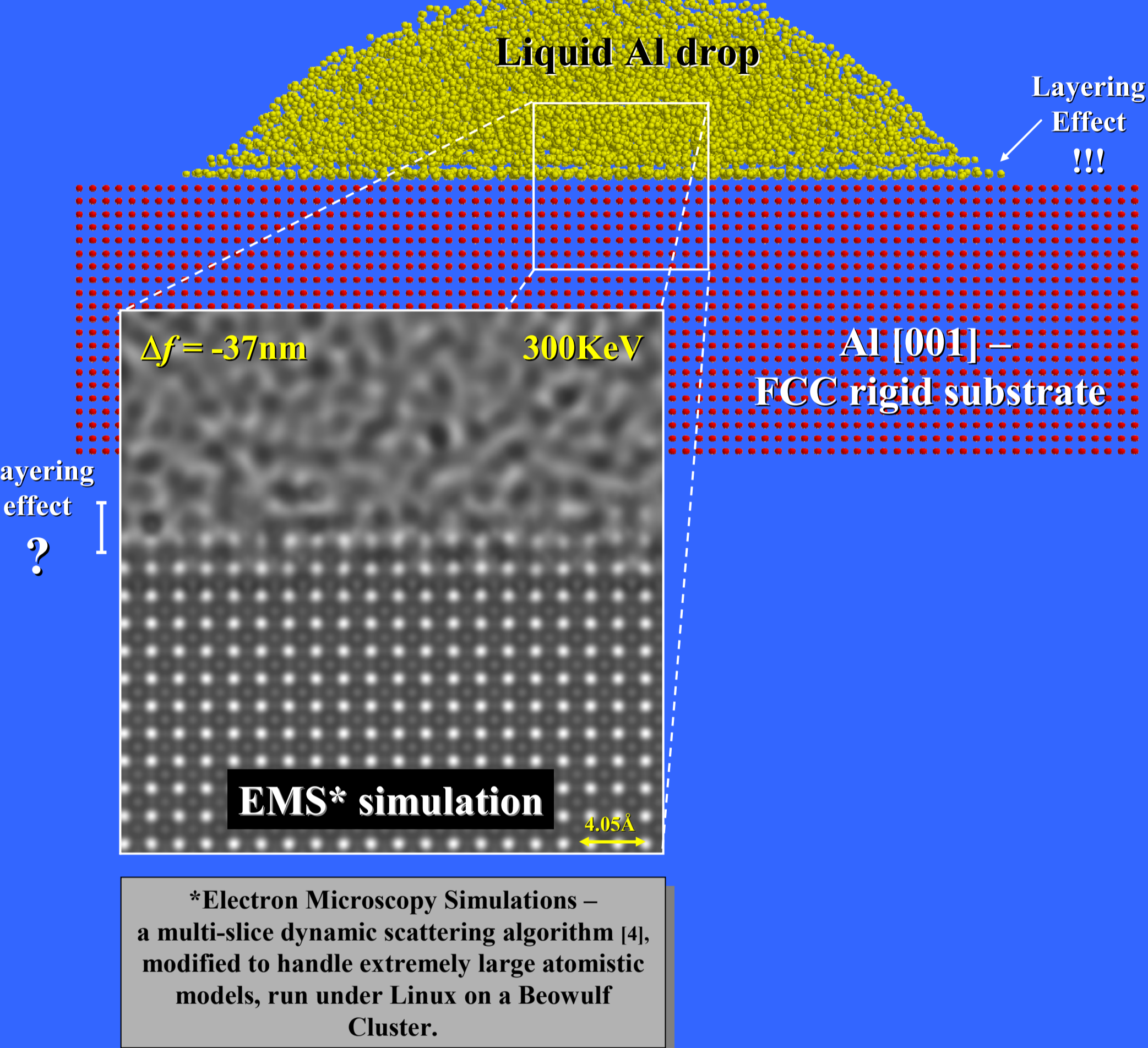
- Objective lens defocus (Δf).
- Astigmatism.
- The size of the objective aperture.
- Interface inclination.
- Z.A. deviation.

The aim of this work:

Define, by means of **computerized HRTEM image simulations (EMS)** combined with **molecular dynamics (MD) simulations**, the exact imaging conditions that will **enable accurate analysis of the layering effect occurring at solid-liquid interfaces**.

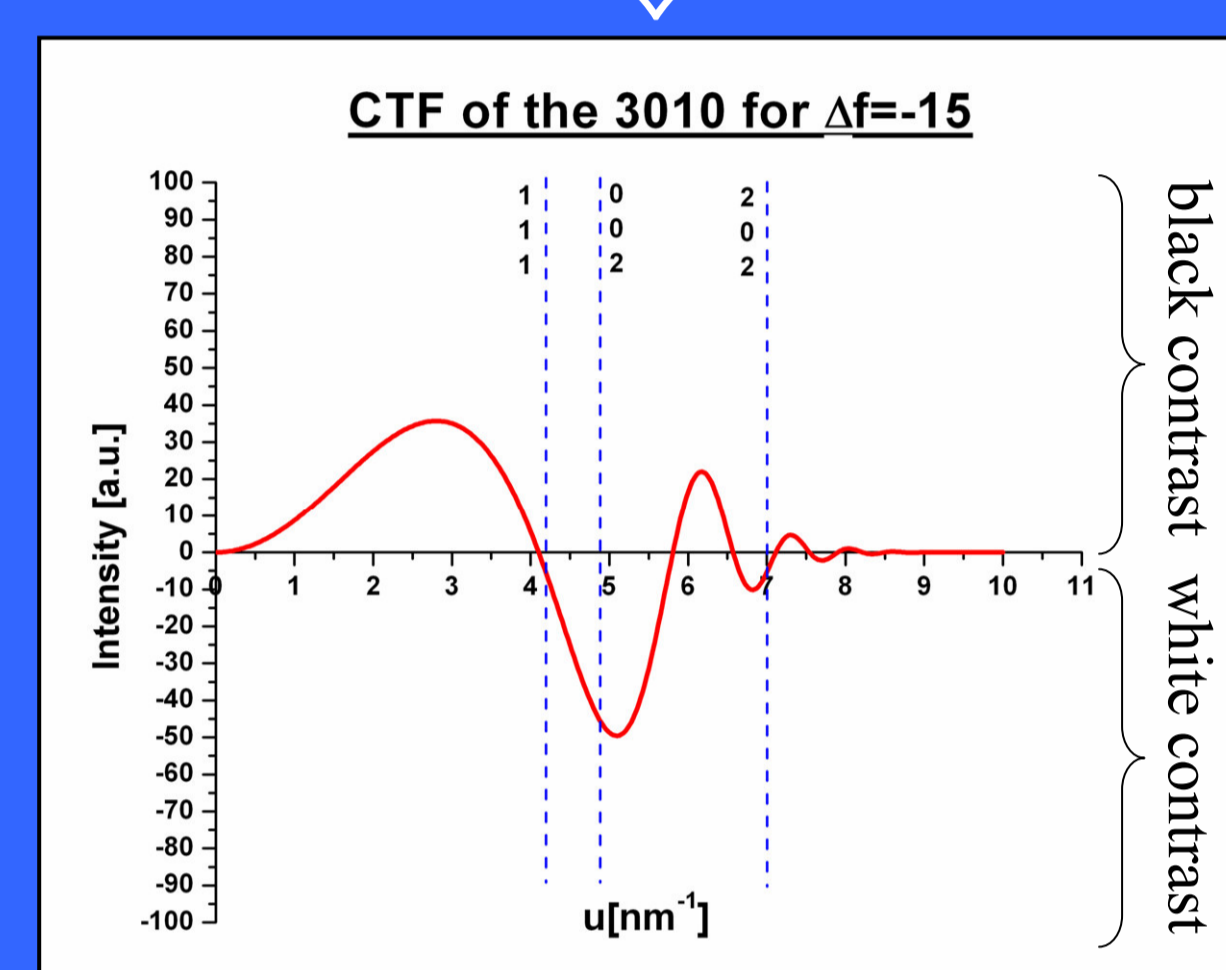
The Simulated Specimens:

Simulated using molecular dynamics (EAM)



Best Defocus Determination:

If white spots = column positions \Rightarrow the image intensity is directly interpretable

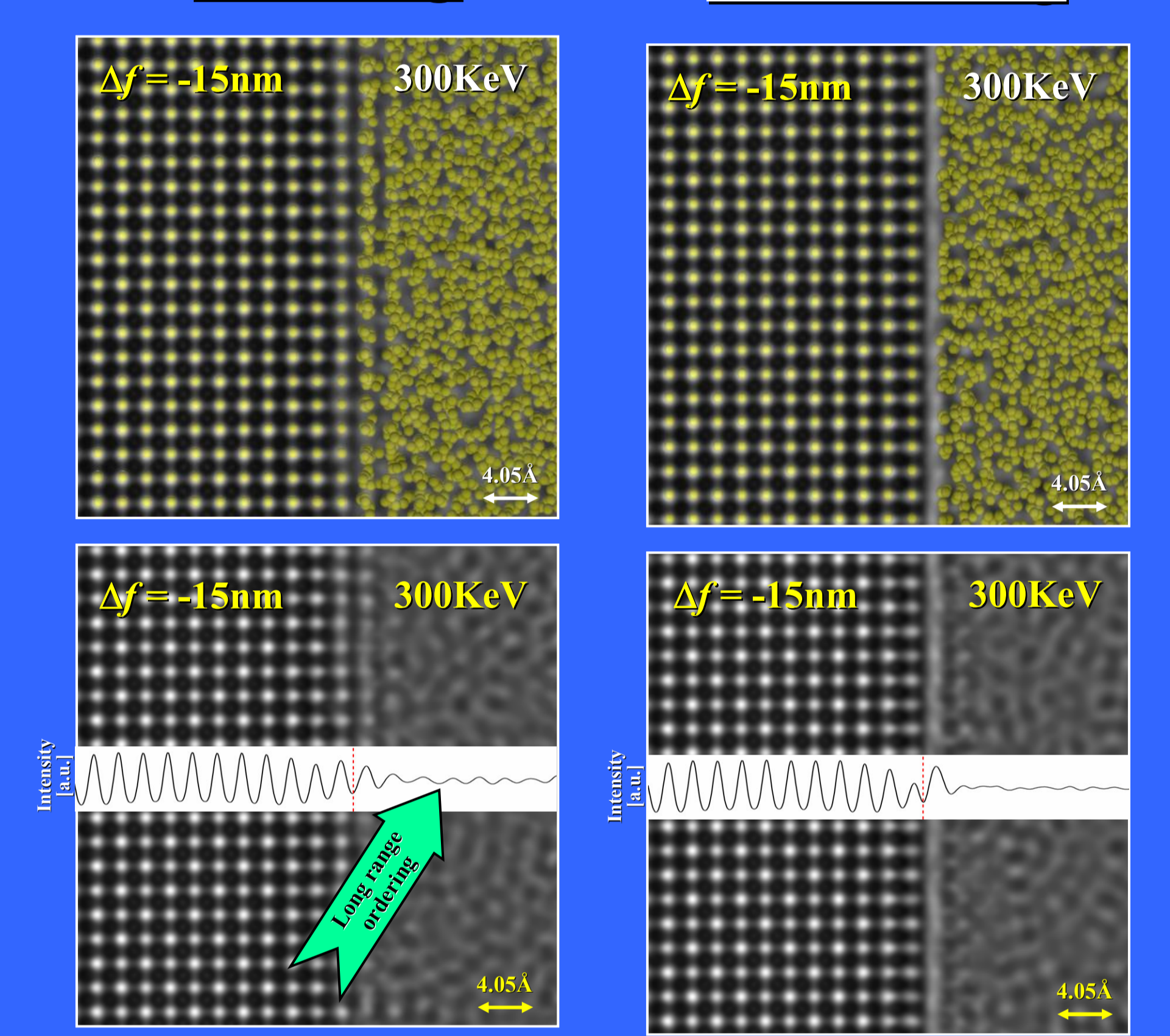


The intensities corresponding to the periodicity of the (002) planes are white.

best $\Delta f = -15 \text{ nm}$

Ordering

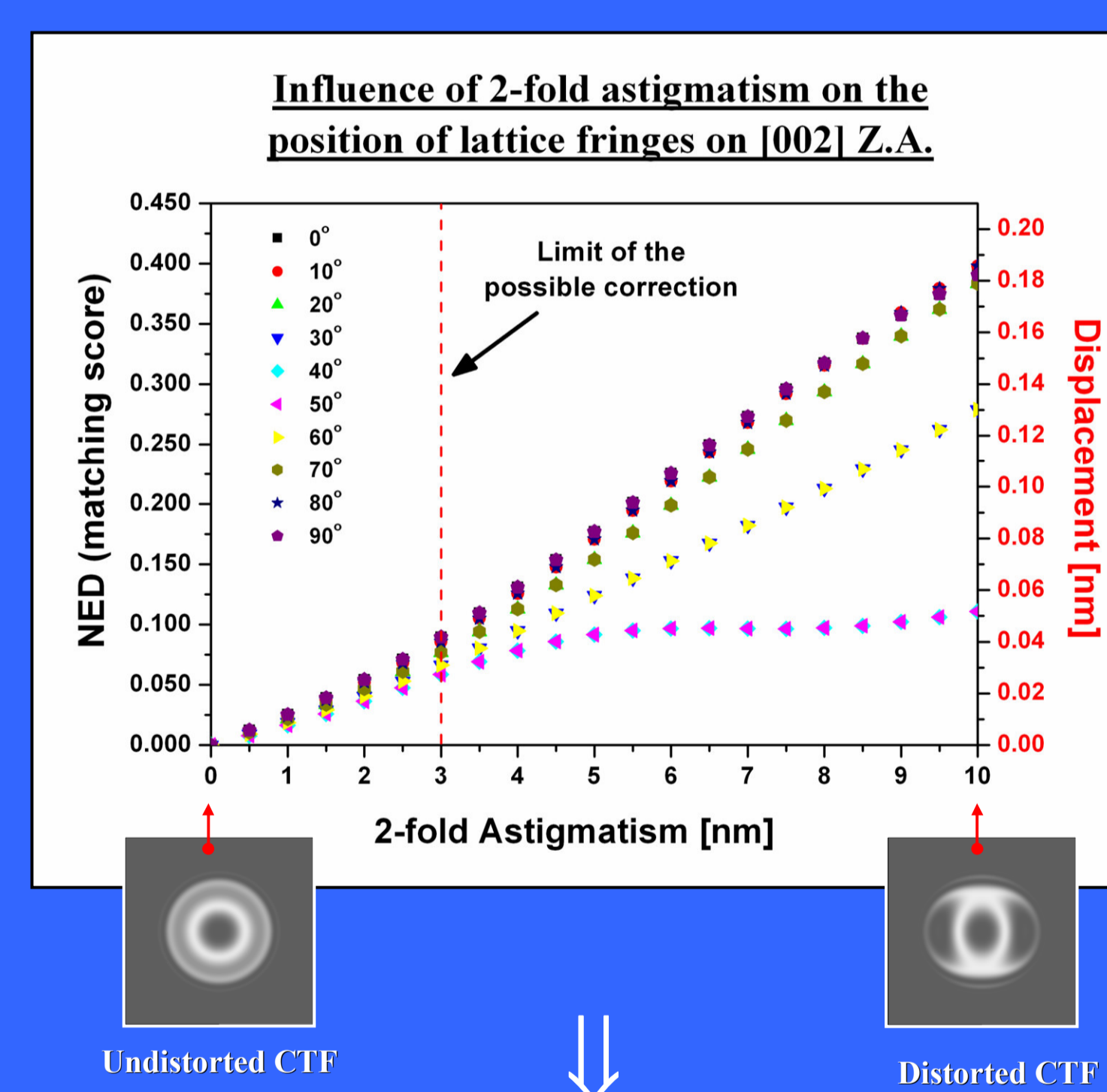
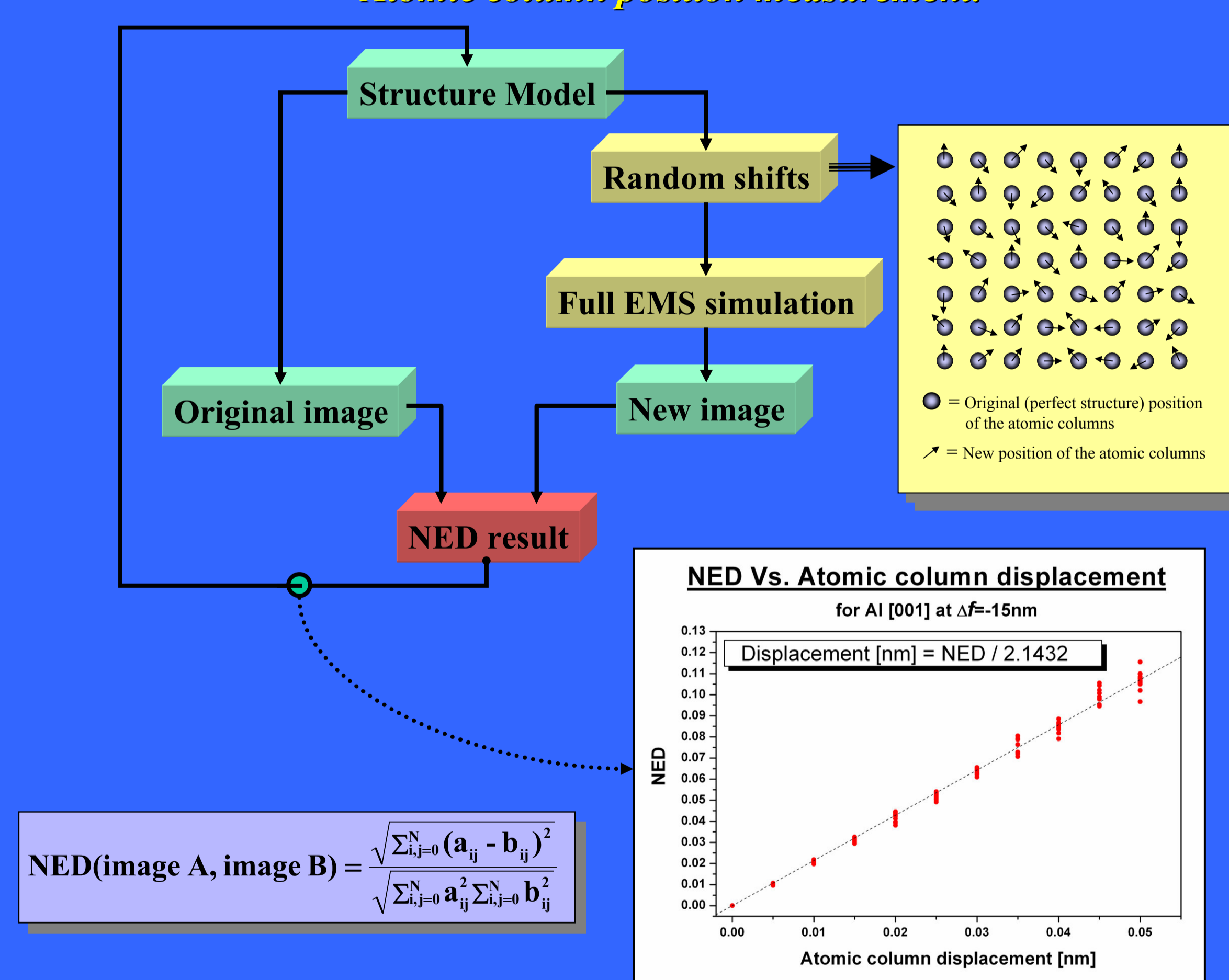
No ordering



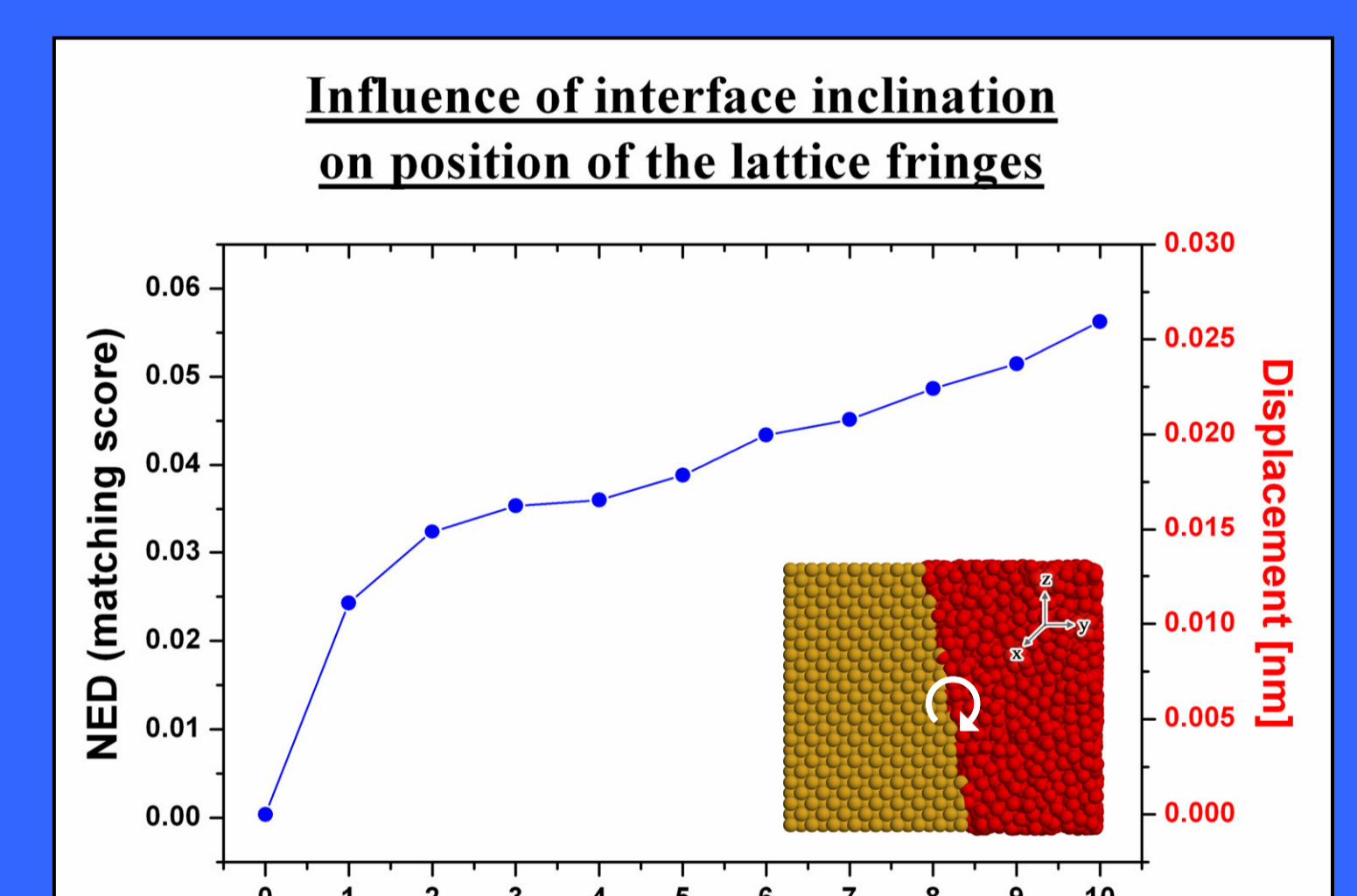
Simulated micrograph of an interface with **ordering**, from MD simulations. Simulated micrograph of an artificial interface with **no ordering**, produced by joining bulk liquid Al (MD) to crystalline Al.

Atomic Column Displacement Simulation

Translation of a metric (NED) to the precision of Atomic column position measurement.



Very significant for large astigmatism !!!



Very significant for large inclination angles !!!

Choose a crystalline-amorphous interface to be studied

Determine the crystallographic orientation of the crystalline part

CTF + EMS simulations

Define the best defocus conditions

Error estimation

- Astigmatism
- Inclination
- Z.A. deviation

NED values

Atomic Column Displacement simulations

Translate NED values to real values

Determine quantitatively the range of the layering and in-plane ordering effect.

Proposed Procedure

Conclusions

- Scherzer defocus is not always the best option for the investigation of solid-liquid interfaces.
- Optimum defocus = f (microscope used & Z.A. of the observed crystalline zone).
- CTF of the microscope + EMS simulations of the specific crystalline orientation = **BEST DEFOCUS**.
- reasonable 2-fold Astigmatism and interface inclination may lead to errors of a few tenths of an Angstrom in the determination of the ordering effect range.

The Future

- Apply the procedure on real systems, such as equilibrium amorphous films, high temperature Cu-Al₂O₃ or Ni-Al₂O₃ interfaces.
- Define a procedure to quantify the in-plane ordering.

References:

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2. W. J. Ma and J. R. Banavaf, J. of Chemical Physics, 97(1):485, 1992.
3. J.M. Howe, Philosophical Magazine A, 74(3):761, 1996.
4. P.A. Stadelmann, Ultramicroscopy, 21:131, 1987.

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